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TRANSMITTAL	Filing Date		mber 30, 2003		
FORM	First Named In	ventor Ulrich	Ulrich Bonne		
(to be used for all correspondence after initial f	ling) Art Unit	Unkn	Unknown		
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Total Number of Pages in This Submission	Attorney booke	H ₀₀₀	5598-0760(1100.123		
	ENCLOSURES	(Check all that apply)		
Fee Transmittal Form Fee Attached Amendment/Reply After Final Affidavits/declaration(s) Extension of Time Request Express Abandonment Request Information Disclosure Statement	Drawing(s) Licensing-related Petition Petition to Converence Provisional Applice Power of Attorney Change of Corres Terminal Disclaim Request for Refure CD, Number of Corres Remarks	rt to a cation y, Revocation pondence Address ner	Appeal C of Appeal Appeal C (Appeal N Proprieta	closure(s) (please	
Certified Copy of Priority Document(s) Response to Missing Parts/ Incomplete Application Response to Missing Parts under 37 CFR 1.52 or 1.53	Form PTO 1449 listing 3 49 non-US patent refere Return Postcard		s and 49 non-US p	2004 AUG 19 OPR/FI	
SIGNA	TURE OF APPLICAN	IT, ATTORNEY, C	R AGENT	5 =	
Firm or John G. Shudy, Jr., Reg. Individual name	No. 31,214				
Signature Win O. Chinh (h.					
Date August 17, 2004					
CI	RTIFICATE OF TRA	NSMISSION/MAI	LING		
I hereby certify that this correspondence is being facsimile transmitted to the USPTO or deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on the date shown below.					
Typed or printed name Lynn Thompson					
Signature	non Thon	up 80W	Date	e August 17, 2004	

This collection of information is required by 37 CFR 1.5. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to 12 minutes to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:

Ulrich Bonne

Confirmation No.: 6759

Serial No.:

10/748,029

Examiner: unknown

Filing Date:

December 30, 2003

Group Art: unknown

For:

PHASED MICRO ANALYZER IV

Docket No.: H0005598-0760(1100.1230101)

INFORMATION DISCLOSURE STATEMENT (37 C.F.R. §1.97(b))

Mail Stop Amendment Assistant Commissioner for Patents PO Box 1450 Alexandria, VA 22313-1450

CERTIFICATE UNDER 37 C.F.R. 1.8: I hereby certify that this correspondence is being deposited with the United States Postal Service on the date shown below with sufficient postage as first class mail in an envelope addressed to the: Commissioner for Patents, PO Box 1450, Alexandria, VA 22313-1450, on this 17th day of August, 2004.

John G. Shudy, Jr.

Dear Sir:

With regard to the above-identified application, the items of information listed on the enclosed Form 1449 are brought to the attention of the Examiner.

This statement should be considered because it is submitted before the mailing date of a first Office Action on-the-merits. Accordingly, no fee is due for consideration of the items listed on the enclosed Form 1449.

In accordance with 37 C.F. R. §1.98(a)(2), a copy of each non-US patent document or other information listed on the enclosed Form 1449 is provided.

No representation is intended to be made hereby that any of the cited references establishes, by itself or in combination with other information, a prima facie case of unpatentability of any claim of the present case.

Consideration of the items listed is respectfully requested. Pursuant to the provisions of M.P.E.P. 609, it is requested the Examiner return a copy of the attached Form 1449, marked as being considered and initialed by the Examiner, to the undersigned with the next official communication.

Respectfully submitted,

Ulrich Bonne

By his attorney,

Dated: 8-17-04

John G. Shudy, Jr., Reg. No. 31,214

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FORM PTO-1449 Page 1 of 4	Atty. Docket No.: H0005598-0760 (1100.1230101)	Serial No.: 10/748,029
. LIST OF PATENTS AND PUBLICATIONS FOR	Applicant: Ulrich Bonn	ne
APPLICANT'S INFORMATION DISCLOSURE STATEMENT	Filing Date: December 30, 2003	Group Art: unknown

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FORM PTO-1449 Page 2 of 4	Atty. Docket No.: H0005598-0760 (1100.1230101)	Serial No.: 10/748,029
LIST OF PATENTS AND PUBLICATIONS FOR	Applicant: Ulrich Bonne	
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· APPLICANT'S INFORMATION DISCLOSURE STATEMENT	Filing Date: December 30, 2003	Group Art: unknown

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	56-153256	11/1981	Japan	Abstract
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•	Applicant: Ulrich Bonne				
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EXAMINER:

DATE CONSIDERED:

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.